



Best Practices for Building Automated Test Systems

Smarter Test for Advanced Aerospace and Defense Electronics



Best Practices Depend on Your Perspective



Latest Consumer Device



B-52 Stratofortress

Challenges of ATS Development and Proliferation

Development

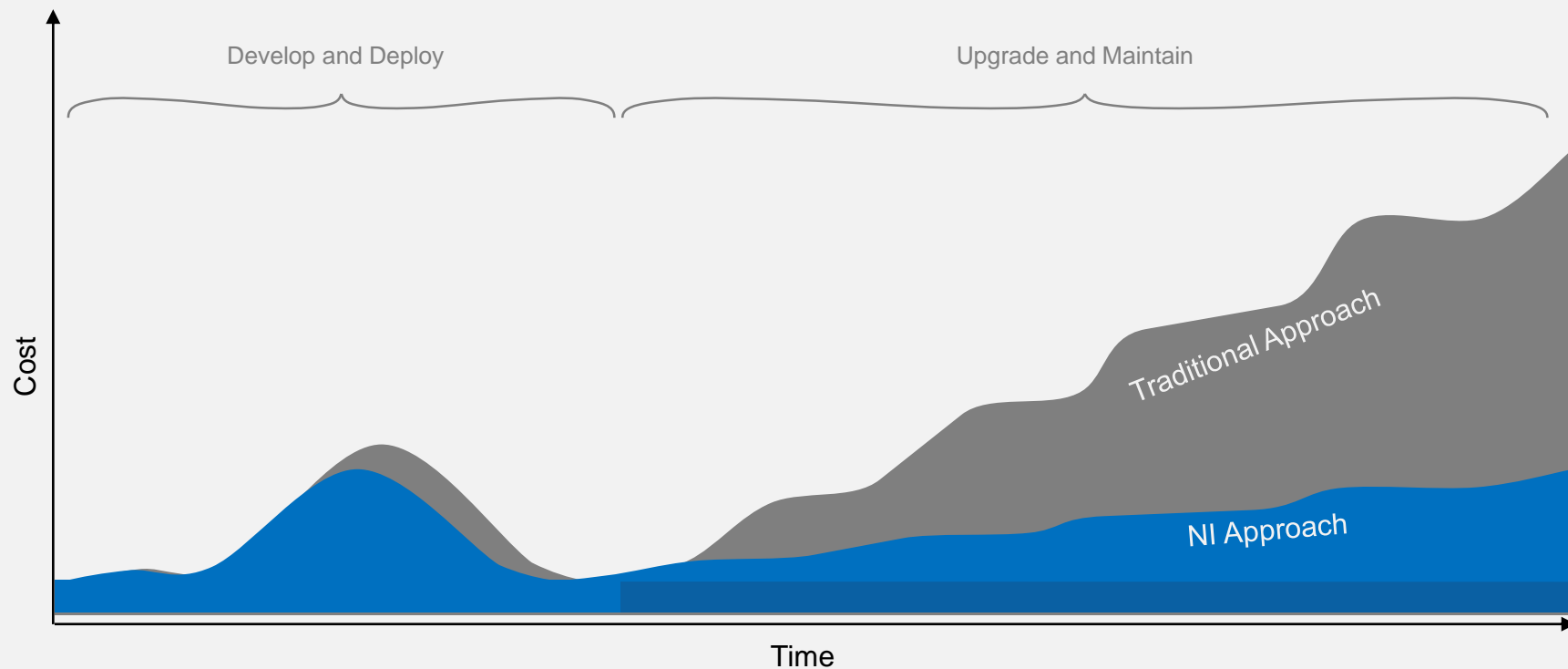
- Fixed schedule & budget
- Future technology insertion
- Common vs. custom

Maintenance

- Long product life cycle
- Obsolete equipment
- Instrument failure
- Costly TPS changes
- Total cost of ownership



Total Cost of Owning an Automated Test System





AEROSPACE
AND DEFENSE

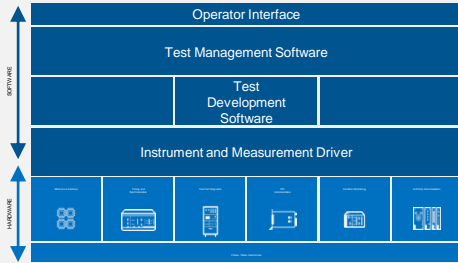
HARRIS

Harris Reduces Cost of Test While Increasing Test Throughput 400% with NI
Harris reduced the cost of test by 74% and increased test throughput by 400 percent with an ROI of 185 percent while carefully maintaining the quality and performance standards that our military radios are known for."

74% Decrease in Cost of Test

83% Reduction in Floor Space

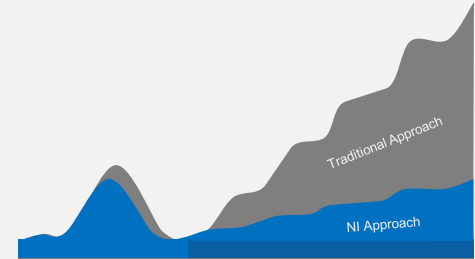
3 Best Practices for Architecting an ATE System



Develop a Scalable &
Reusable Software Architecture



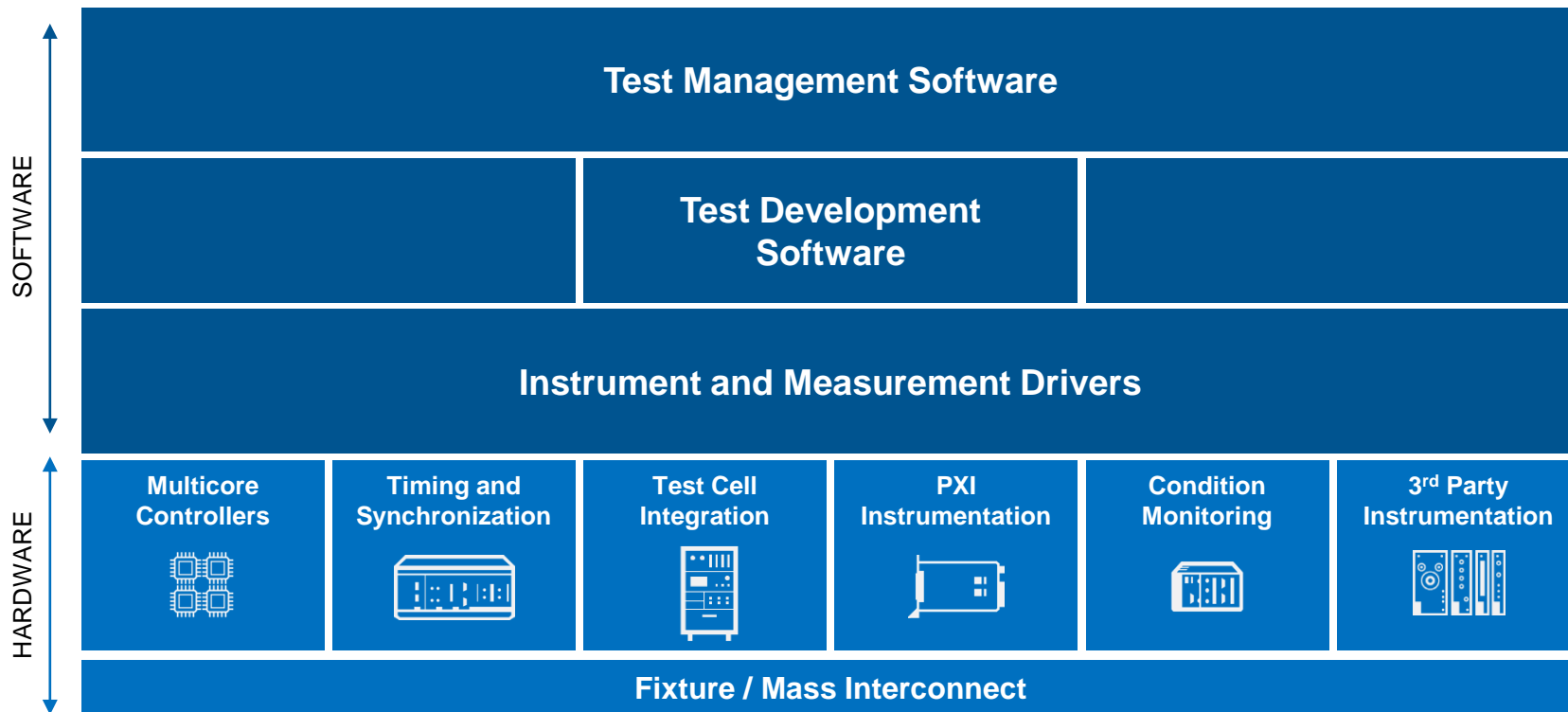
Standardize on the Latest
Off-the-Shelf Hardware



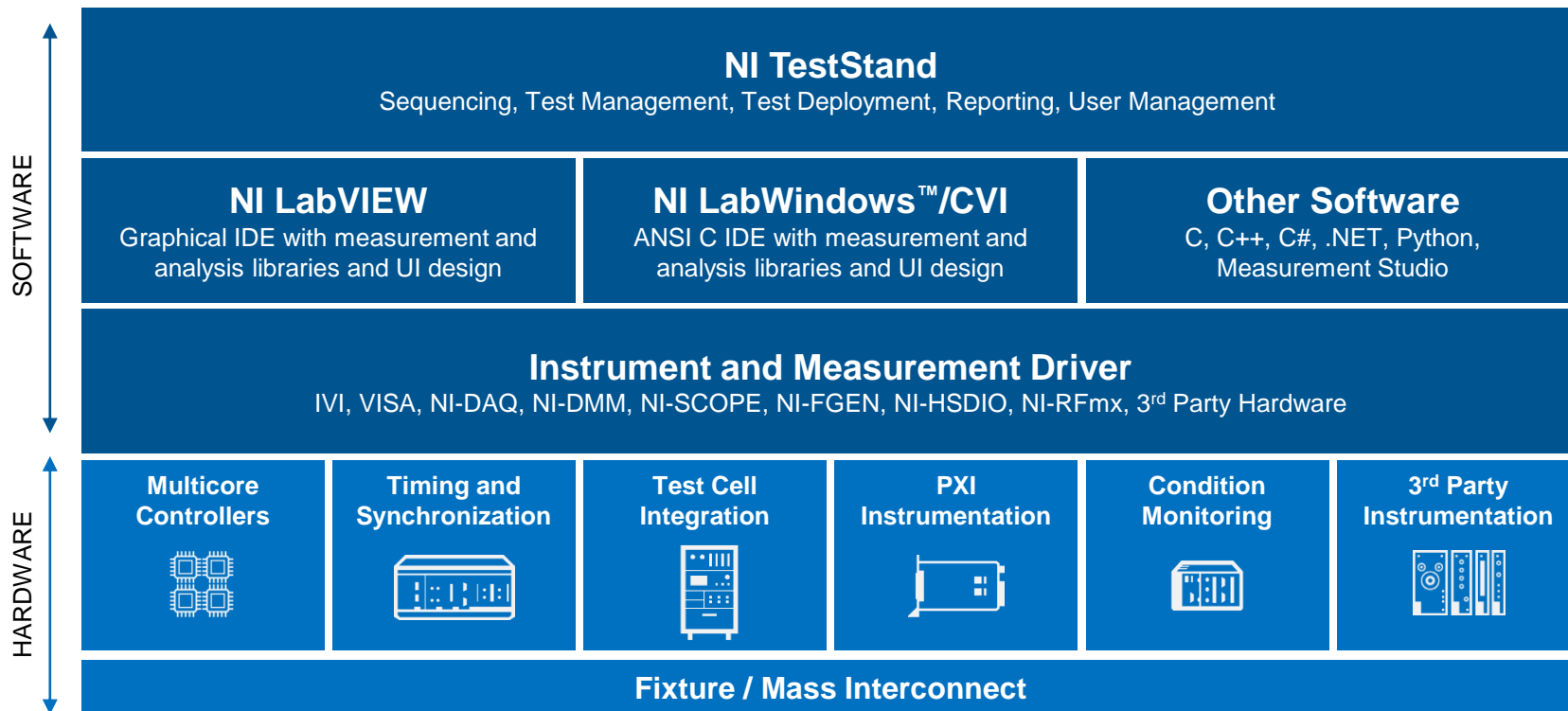
Plan for
Obsolescence

Develop a Scalable & Reusable Software Architecture

Architecture of an Automated Test System



Architecture of an Automated Test System



Separating Software Responsibilities

COMMON

Test Management Software

- Limit checking
- Integration of system-level requirements
- Results processing
- Shared measurements
- Operator interface
- User management
- Test flow control

UNIQUE

Test Development Software

- Instrument control
- Stimulus
- Analysis code
- DUT control
- DSP
- Tracking of individual test requirements

TestStand

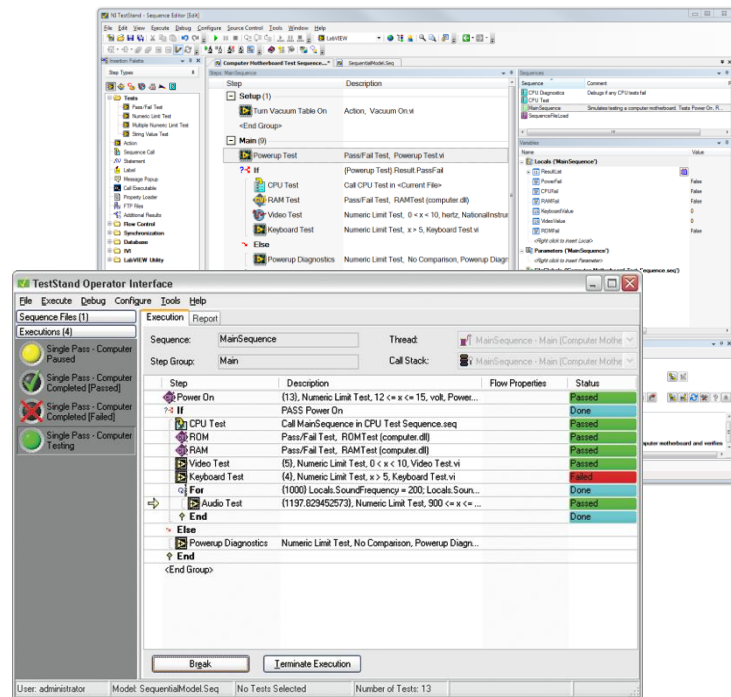
Industry-Standard Test Management Software

- Author, execute, and debug test sequences
- Leverage test code developed in **any language**
- Test many devices in parallel
- Generate reports
- Integrate with databases
- Extend the software to meet custom requirements
- Develop professional operator interfaces

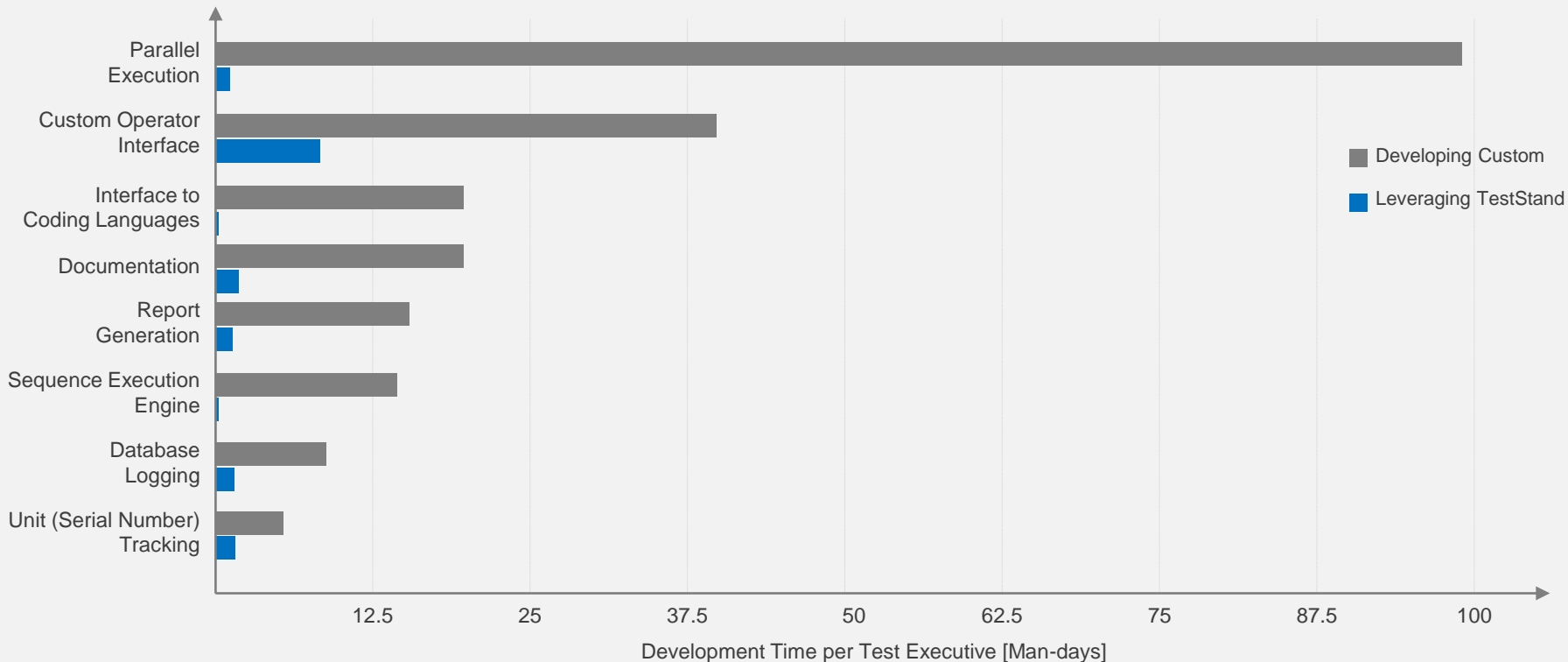
6,000+
COMPANIES
WORLDWIDE

10,000+
EXISTING
DEVELOPERS

1500+
NEW DEVELOPERS
TRAINED ANNUALLY

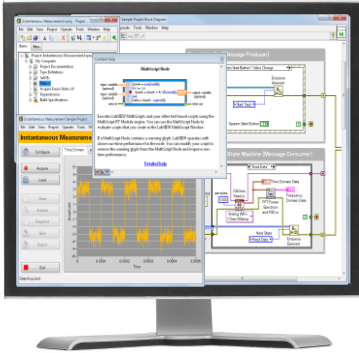


Increase Productivity with COTS Test Management Software



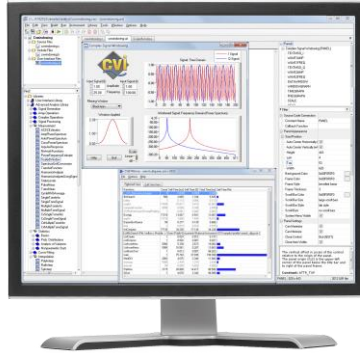
TPS Application Development Environments (ADEs)

NI LabVIEW



System Design
Software

NI LabWindows/CVI



Proven ANSI C IDE &
Engineering Toolbox

NI Measurement Studio

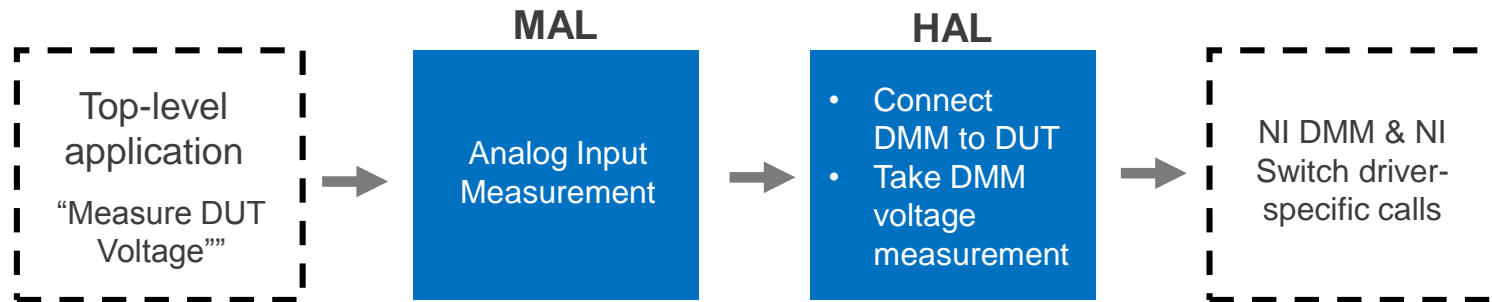


.NET Tools Designed
for Engineering

Architecting for Scalability and Reusability

Hardware Abstraction Layer (HAL): layer of programming that allows an automated test system to interact with a hardware device at a general or abstract level rather than at a detailed hardware level

Measurement Abstraction Layer (MAL): layer of programming that allows an automated test system to interact with a DUT through high-level actions rather than at a detailed hardware level



Implementing an Abstracted Architecture

Abstraction is a spectrum –
start by taking advantage of out-of-the box abstraction layers

Hardware Abstraction

- NI family drivers
 - NI DMM support for all 40XX instruments
- IVI compliant drivers



- Custom HAL

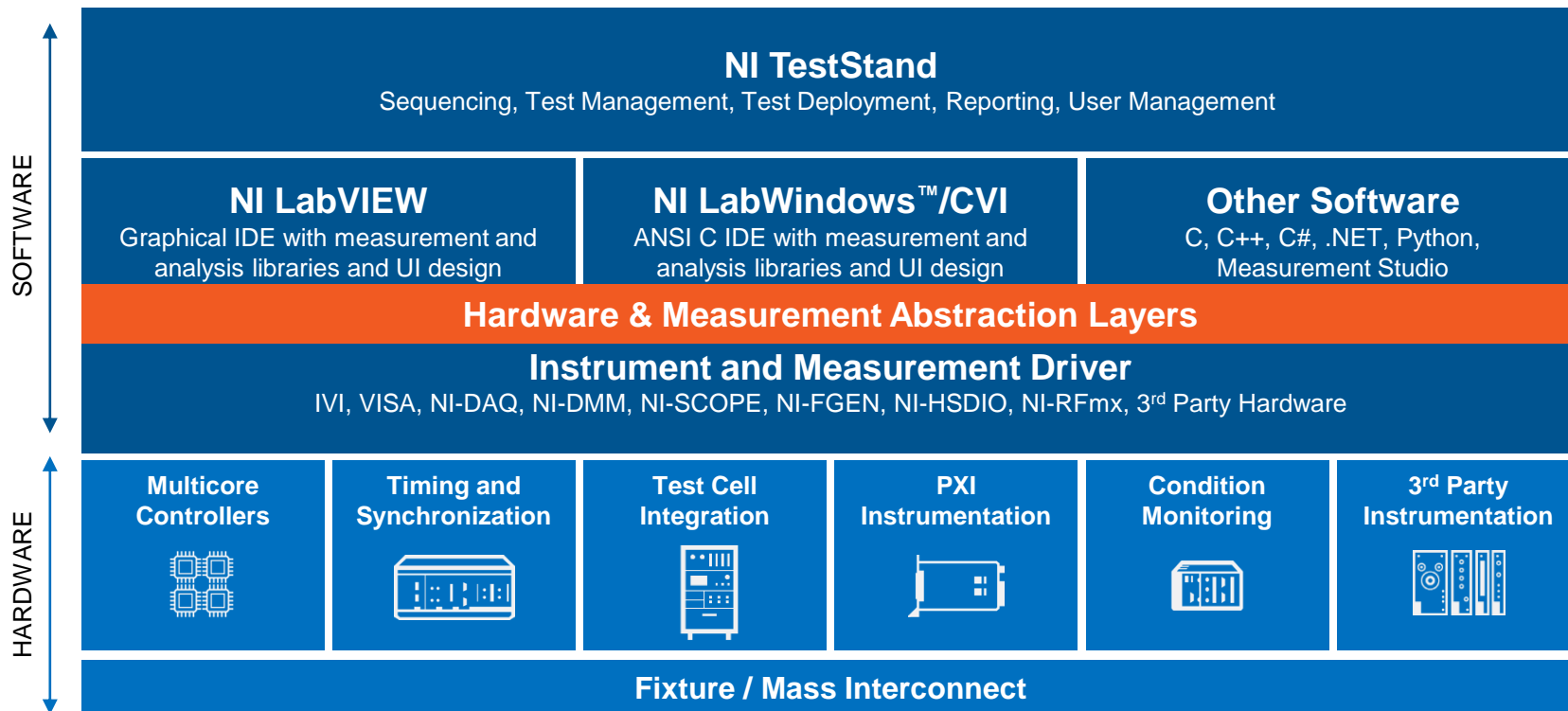
Measurement Abstraction

- TestStand Custom Step Types
- LabVIEW subVIs
- NI Switch Executive

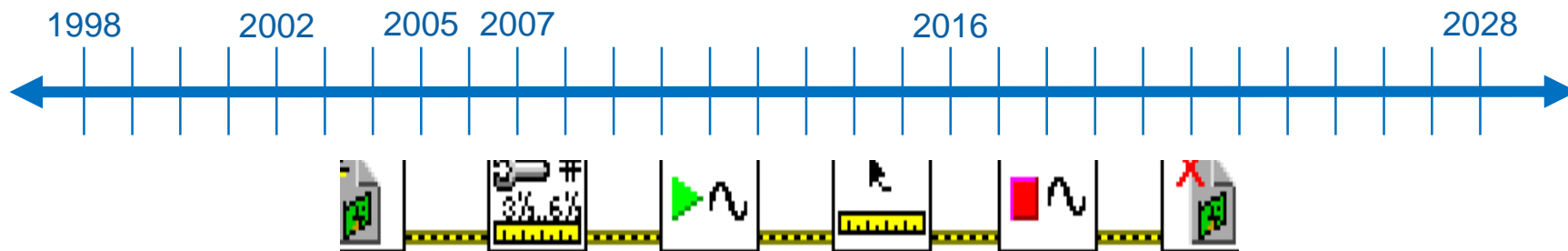
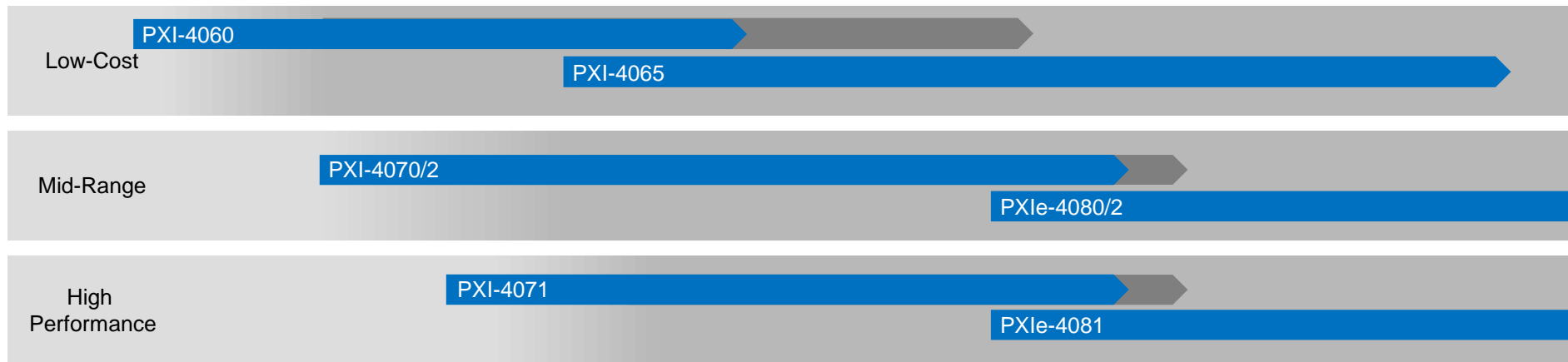


- Custom MAL

Hardware and Measurement Abstraction Layers



NI-DMM Hardware Abstraction





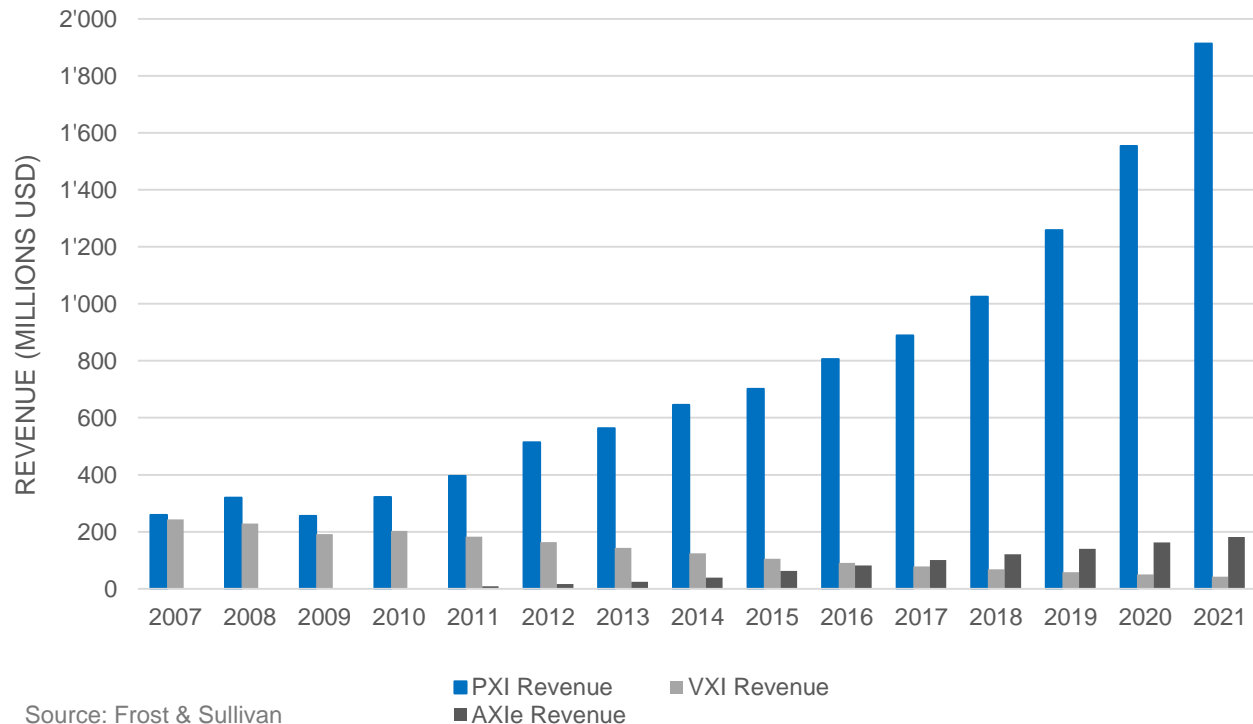
9X Reduction in Test Development Time

60% Code Reuse

“By leveraging commercial off-the-shelf software technologies such as TestStand and LabVIEW, our Automated Test Engineering team was able to achieve up to 60 percent code reuse for each automated test and reduce overall test development time by up to 9X. Using the NI certification program, coupled with in-house training, we were able to develop the skills necessary to produce robust, flexible code and maintain it across over 200 test benches.”

Standardize on the Latest Off-the-Shelf Hardware

Modular Instrumentation (PXI) Drives ATE



Source: Frost & Sullivan

- Founded in 1997
- 60+ Vendors
- 2000+ Modules
- Latest Technology
- Growing Market Share

NI's Industry-Leading Test & Measurement Platform



PXIe-5162
4ch, 1.5GHz,
10-bit Digitizer



PXI-4081
7½-digit, 1kV Precision
DMM



PXIe-5668R
26.5 GHz VSA with
765 MHz Bandwidth



PXIe-4135
Precision System SMU
10 fA Sensitivity



PXIe-5646R
6GHz Vector Signal
Transceiver



PXIe-1085
PXI Chassis
24 GB/s Throughput



PXIe-8880
PXIe Controller
8 Core Intel Xeon



NI LabVIEW
System Design
Software



NI TestStand
Test Management
Software



PXIe-2543
6GHz, 8ch, Solid-State Mux

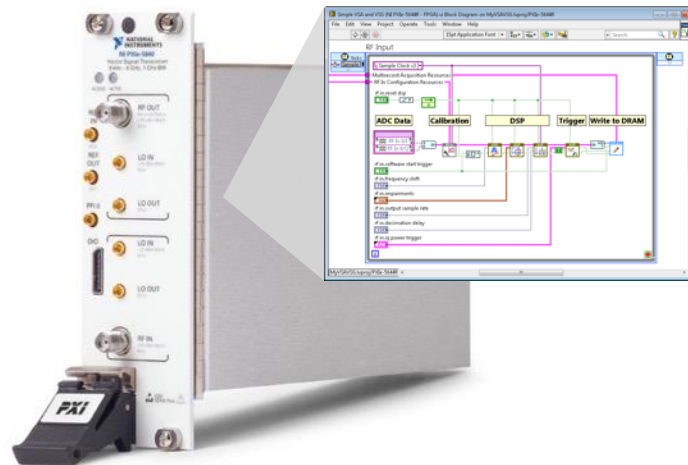
2nd Generation Vector Signal Transceiver

Features at a Glance

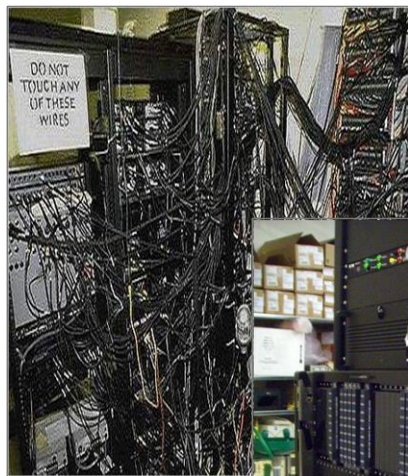
- User-programmable FPGA with LabVIEW
- 1 GHz of instantaneous bandwidth for advanced digital predistortion test and wideband signals
- Excellent accuracy enables measurement of 802.11ax error vector magnitude performance of -50 dB
- FPGA enables measurement speeds up to 10X faster than traditional instrumentation
- Small size and tight synchronization allow for up to 8x8 MIMO configuration in a single 18-slot chassis

Application Areas

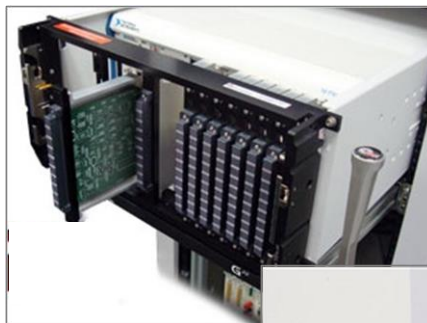
- Wireless test
- Semiconductor test
- Automotive radar



Mass Interconnect and ITAs



VS.



PCB-Based
or
Cabled Connection



Diagram illustrating the test system architecture components and their connections:

- UUT I/O (protected)**: The User Under Test (UUT) I/O interface, shown as a black box with a handle.
- Enclosure**: The protective housing for the UUT I/O interface.
- ITA frame (reliable engagement)**: The Interface Test Assembly (ITA) frame, which provides reliable engagement for the UUT I/O interface.
- Receiver Assembly (highly tolerated and robust)**: The Receiver Assembly, which is highly tolerated and robust, connected to the ITA frame.
- PXI Chassis (expensive asset)**: The PXI Chassis, which is an expensive asset, connected to the Receiver Assembly.
- I/O cabling (defined distance)**: The I/O cabling, which is defined distance, connecting the Receiver Assembly to the PXI Chassis.

Standardize, Standardize, Standardize

How many DC programmable power supplies are in your library?

How about 6½-digit DMMs?

General Rule:

Standardize what you can, as fast as you can,
if the differences aren't adding value.

NI ATE Core Configurations Make Standardization Easier

Standardized starting point for in-house ATE development



40U Configuration

24U Configuration



Category	Details
Mechanical	40U and 24U Rack Height with industrial-grade casters and mounting rails
Power	Power Distribution Unit, Power Entry Panel, and Optional Uninterruptible Power Supply
Safety	Emergency Power Off, Thermal Shutdown, Multi-Level Circuit Protection
Instrumentation	PXI, cDAQ, cRIO, SLSC, 3 rd Party
Cooling	24 VDC Fan Kit, Air Filtration
Cabling	Integrated Cable Management and 10/100 ENET Switch

Plan for Obsolescence

Life Cycle Management Practices



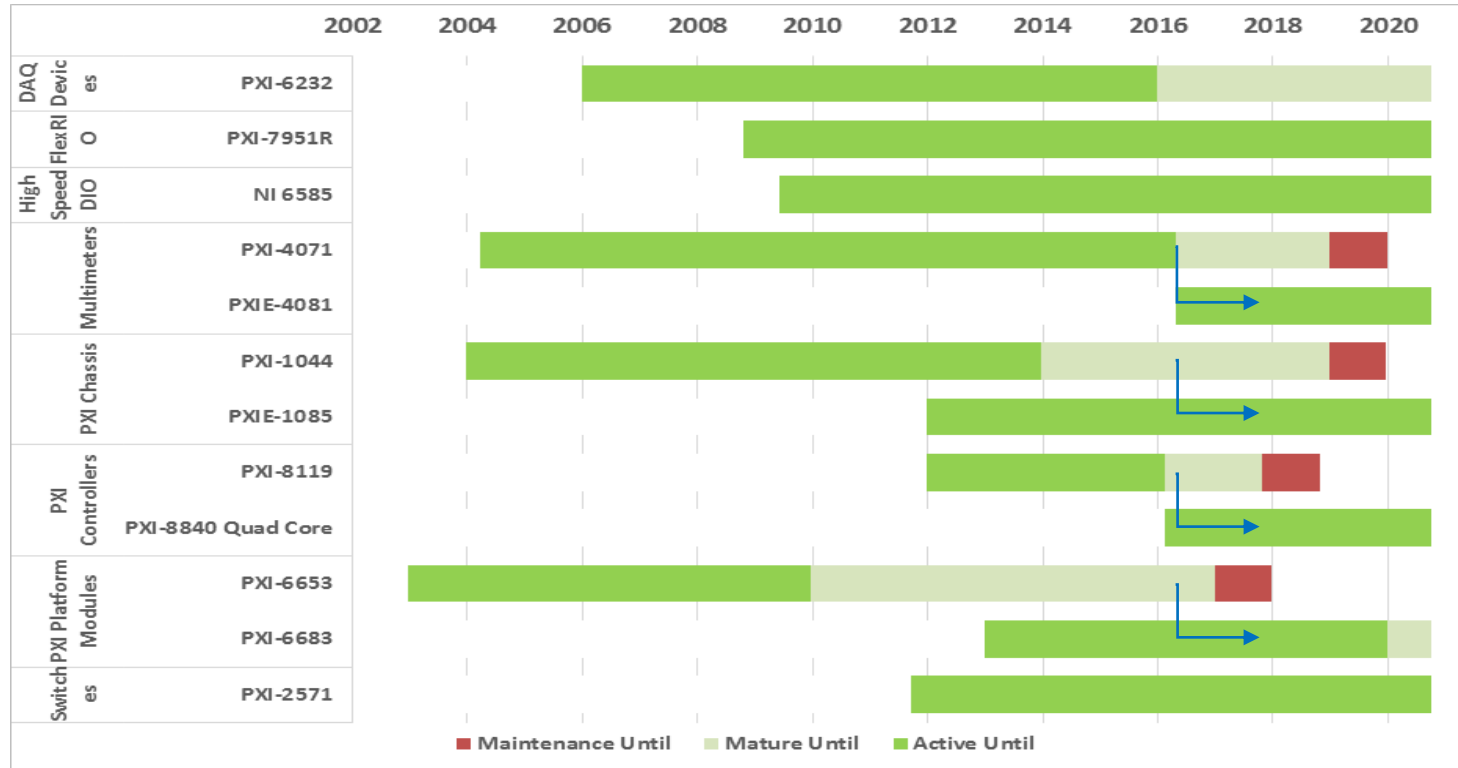
Proactive / Strategic

- Modular open architectures
- Technology roadmapping
- Planned system upgrades
- Technology insertion planning
- Life cycle analysis and monitoring
- Formal lifecycle strategy

Reactive / Tactical

- Alternate source
- Substitution
- Redefine requirement
- Emulation
- Lifetime Buy
- Redesign
- Reverse Engineer
- Reclamation

Example Life Cycle Analysis





23% Decrease in LRU Repair Time

80% Reduction in Quality Deficiency Reports

18 Obsolete Test Set Replaced

“CACI selected many NI instruments for the core of the CBATS test system based on the relationship with the company and the quality of its products. CACI’s relationship with NI has grown to a level of mutual trust as we work together to deliver high-quality, sustainable test solutions at affordable prices.”

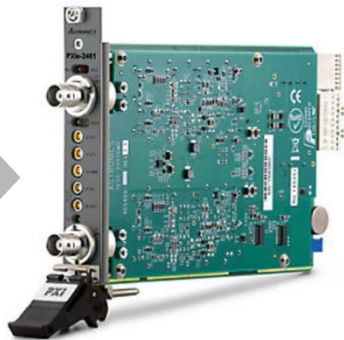
CACI

NI and Astronics Collaborate on VXI to PXI Transition



Astronics VXIbus 2461C

2-channel, 200 MHz Frequency Time Interval Counter



Astronics 2461 for PXI Express

2-channel, 200MHz Frequency Time Interval Counter



Astronics PXIe-2461

2-channel, 200MHz Frequency Time Interval Counter

Astronics PXIe-6943

32-channel, 200MB/s Digital I/O Module

Astronics PXIe-3352

Rubidium Clock Source Module

Astronics PXIe-1209

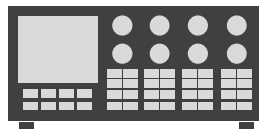
100MHz Pulse Pattern Generator Module

“Full TPS and Driver Compatibility”

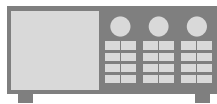
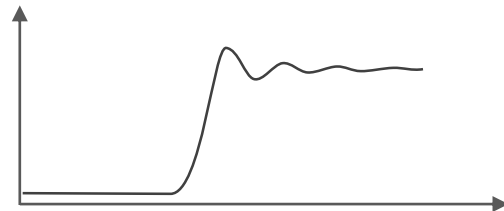
Emulating Legacy Instrumentation

Challenge

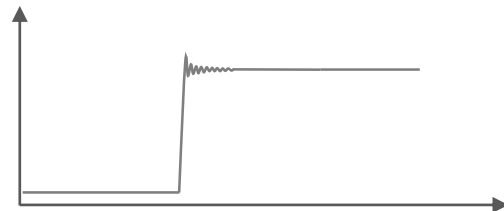
- Previous Instrument is End-of-Life
- New Instrument Behavior
- Test System Depends on Old Behavior
 - Trigger Types
 - Analog Bandwidth
 - Sampling Rate
 - Dynamic Range



Legacy Instrument

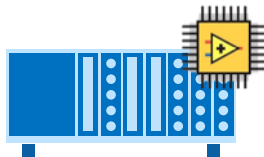


New Box Instrument

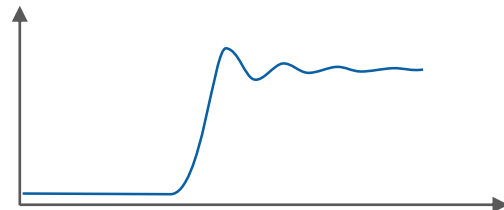


Solution

- Software-Defined Instrumentation
- Digital Signal Processing
- FPGA Technology



Software-Defined Instrument





Real-Time Spectrum Analysis

100% POI with Full Accuracy on 320 ns Minimum Duration Signals from 20 Hz to 26.5 GHz

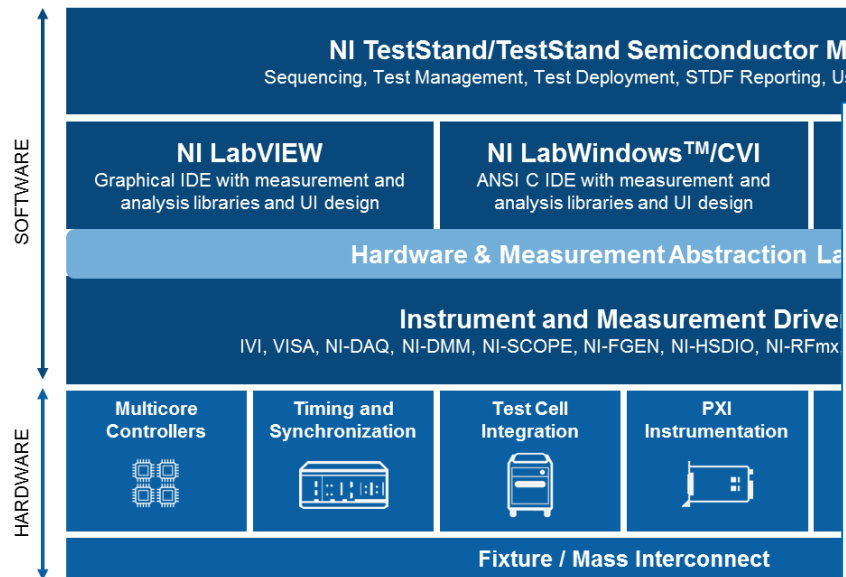
765 MHz analysis BW and real-time DSP throughput of up to 62 million FFTs

“NI’s PXIe technology provides unparalleled scalability, upgradeability and technology insertion capability that minimizes obsolescence, repair and test program portability issues that plague box instruments”



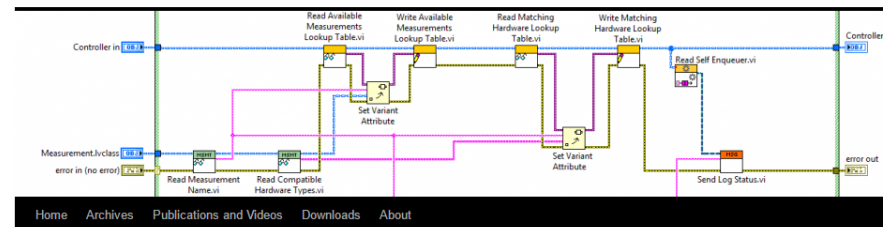
Summary

Architecture of an Automated Test System With Abstraction



Software Engineering for LabVIEW

A Guide to Graphical System Design



← 2013 CLA Summit Kick-Off

Getting Started with LabVIEW in Under 10 Minutes →

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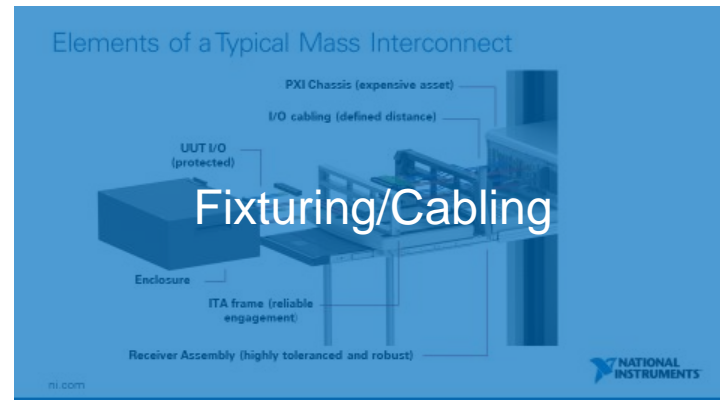
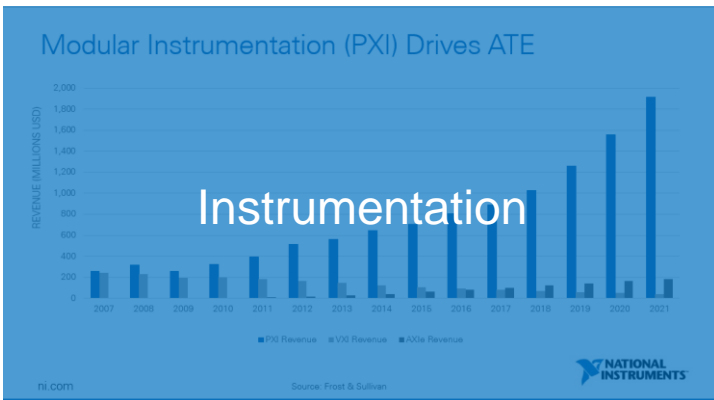
Designing and Deploying a Plug-in LabVIEW Measurement System with Multiple Abstraction Layers Using the Actor Framework

Posted on [March 28, 2013](#)

★★★★★ 9 Votes

I developed the [Measurement Framework](#) over the last year in order to experiment with and explore some of the latest architectures, technologies and design approaches that are becoming increasingly important for large LabVIEW systems. I've used sections of this application to illustrate technical topics in previous posts, but I wanted to use today's entry to explore the overall design of this system and several of lessons I learned. My hope is to provide insights for any of you that are attempting to address similar requirements. I also hope to lay the groundwork to some deeper-dives into some of these topics in future entries.

ATE Hardware Architecture Considerations



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Standardization

ni.com



Global Service and Support, Locally Delivered



*Provides NI Repair, Calibration, and Inventory Services



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